

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5158	382/245,246,225,168,250,251,248,239,238;348/405.1,416.1,414.1,419.1,417.1,418.1,422.1;375/240.2,240.03,240.22,243,245.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:02
L2	16	L1 and size near3(reduc\$6 or decreas\$3 or lower\$4 or target)with image same ("q-table" or quantiza\$4 near3 table)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:02
L3	4	L2 and ((estimat\$6 or determin\$3 or obtain\$3)near7 scal\$4) same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:03
L4	27	size near3(reduc\$6 or decreas\$3 or lower\$4 or target)with image same ("q-table" or quantiza\$4 near3 table)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:04
L5	6	L4 and scal\$4 same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:05
L6	2	(estimat\$6 near3 reduc\$4 with scal\$4 near3 factor) same target near3 size	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:06
L7	61	(size near3(reduc\$6 or decreas\$3 or lower\$4 or target)) same ("q-table" or quantiza\$4 near3 table)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:06
L8	7	L7 and scal\$4 same (target near3 (size or value))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/13 18:06

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